

January 23 – 24, 2017 | The Florida Hotel & Conference Center | Orlando, Florida

TE-13 | Tuesday, January 24 | 8:00 AM – 5:00 PM | One Day

Course Title: Measurement Uncertainty – Fundamental Applications

Instructor: Dilip Shah, E=MC3 Solutions

Topic: Measurement Uncertainty

Technical Level:

Beginner – course content is designed for students with no previous experience

Intermediate – students must possess as a basic understanding of course concepts

Course Description:

This is a full-day, beginner to intermediate level workshop targeted towards metrologists, technicians and engineers. This workshop will also be useful for specifiers of calibration services. This workshop covers the Measurement Uncertainty fundamentals for metrology professionals new to the subject. Statistical concepts relevant to Metrology and Measurement Uncertainty are introduced, explained and demonstrated. The process of measurement uncertainty estimation is demonstrated per the guidelines from the ISO Guide to the Expression of Uncertainty in Measurement (GUM).

Instructor Biography:

Dilip A. Shah (Fellow of the American Society for Quality) has over 40 years of industry experience in metrology, electronics, instrumentation, measurement and computer applications of statistics in the Quality Assurance areas. He is currently a Principal of E = mc3 Solutions, a consulting practice that provides training and consulting solutions in ISO/IEC 17025, ISO/IEC 9001 and Measurement Uncertainty.